

<b>Notice of References Cited</b>	Application/Control No. 10/749,235	Applicant(s)/Patent Under Reexamination LEE, JONG-CHAN	
	Examiner Christopher P. Schwartz	Art Unit 3683	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,767,015	10-1973	Odier, Jean Alfred	188/71.6
	B	US-4,460,253	07-1984	Kawai et al.	396/258
	C	US-5,485,901 a	01-1996	Akima et al.	188/164
	D	US-5,746,294	05-1998	Lee, Jae-Woong	188/163
	E	US-5,821,712 a	10-1998	Fittje, James E.	318/376
	F	US-6,119,828 a	09-2000	Parsons, Francis Edward	188/250E
	G	US-6,439,355 b1	08-2002	Kimble, Michael E.	188/171
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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